

Substitute Form PTO-1449

U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
12732-225001Application No.  
10/814,159**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

Applicant  
Shunpei Yamazaki et al.Filing Date  
April 1, 2004Group Art Unit  
2879

(37 CFR §1.98(b))

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
WSL	AL	3408154	03/14/2003	JAPAN			ABS	
	AM							
	AN							
	AO							
	AP							

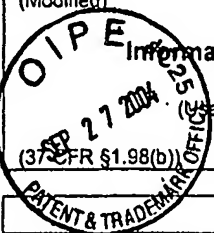
**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
WSL	AQ	Exhibition of Active Matrix Type Organic EL Display at "13 <sup>th</sup> Flat Panel Display Manufacturing Technology Expo & Conference" by ELDis Group (in Japanese with full translation); July 2, 2003
	AR	Documents distributed in the "13 <sup>th</sup> Flat Panel Display Manufacturing Technology Expo & Conference" by ELDis Group (5 pages)
	AS	"Two-way display developed"; <i>The Japan Times</i> ; (1 page); July 3, 2003
	AT	"Mass Production of Organic EL Devices"; <i>Shimotsuke Newspaper</i> (in Japanese with full translation); July 3, 2003

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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WSL	AL	JP 3408154	19 MAY 2003	JAPAN			Full	
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4/15/04

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